United States Patent [19]

Leedy

[11] Patent Number:

4,924,589

[45] Date of Patent:

May 15, 1990

[54] METHOD OF MAKING AND TESTING AN INTEGRATED CIRCUIT

[76] Inventor: Glenn J. Leedy, 1061 E. Mountain Dr., Santa Barbara, Calif. 93108

[21] Appl. No.: 194,596

[22] Filed: May 16, 1988

[56] References Cited

U.S. PATENT DOCUMENTS

:			
	3,405,361	10/1968	Kattner et al
	3,618,201	11/1971	Makimoto et al 437/8
	3,702,025	11/1972	Archer 437/8
	3,762,037	10/1973	Baker et al 437/8
	3,781,670	12/1973	McMahon, Jr 324/73 PC X
	3,795,972	3/1974	Calhoun 437/8
	3,795,975	3/1974	Calhoun et al 437/8
	3,835,530	9/1974	Kilby 437/8
	3,969,670	7/1976	Wu 437/8 X
	3,993,934	11/1976	Baker et al 437/8 X
	4,573,008	2/1986	Lischke .
	4,590,422	5/1986	Milligan .
	4,617,730	10/1986	Geldermans et al
	4,715,928	12/1987	Hamby .

OTHER PUBLICATIONS

IBM Tech. Discl. Bull., vol. 10, No. 10, Mar. 1968, pp. 1466-1467 by Dill et al.

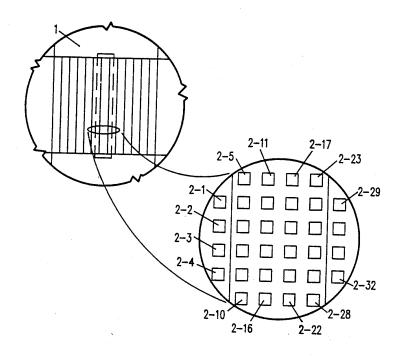
Primary Examiner—Carl J. Arbes Attorney, Agent, or Firm—Skjerven, Morrill, MacPherson, Franklin & Friel

[57] ABSTRACT

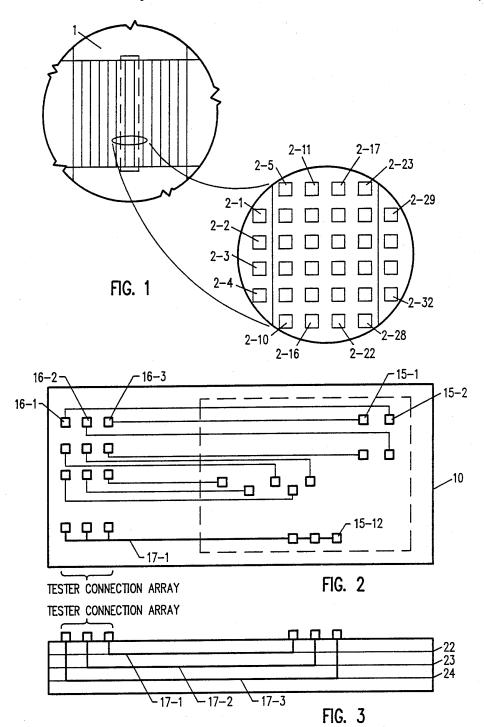
Each transistor or logic unit on an integrated circuit wafer is tested prior to interconnect metallization. By CAD means, the transistor or logic units placement net list is revised to substitute redundant defect-free logic units for defective ones. Then the interconnect metallization is laid down and patterned under control of a CAD means. Each die in the wafer thus has its own interconnect scheme, although each die is functionally equivalent, and yields are much higher than with conventional testing at the completed circuit level.

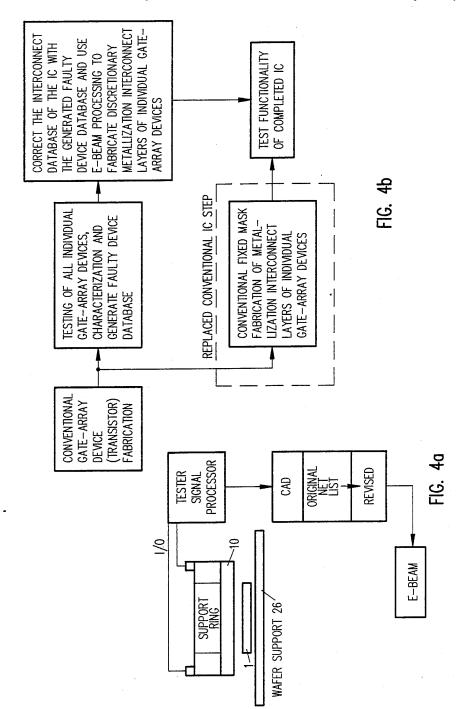
The individual transistor or logic unit testing is accomplished by a specially fabricated flexible tester surface made in one embodiment of several layers of flexible silicon dioxide, each layer containing vias and conductive traces leading to thousands of microscopic metal probe points on one side of the test surface. The probe points electrically contact the contacts on the wafer under test by fluid pressure. The tester surfaces traces are then connected, by means of multiplexers, to a conventional tester signal processor.

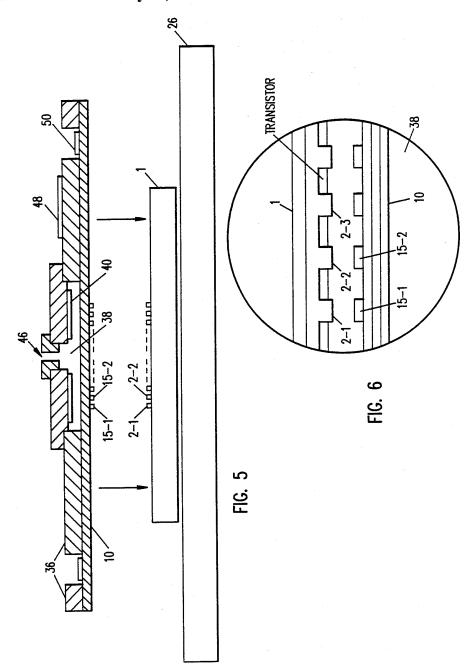
20 Claims, 16 Drawing Sheets











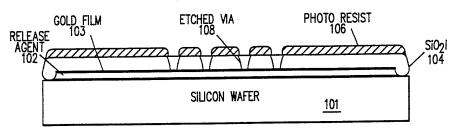


FIG. 7

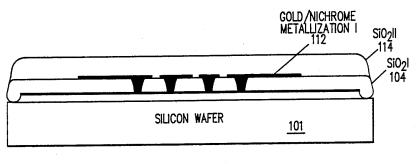


FIG. 8

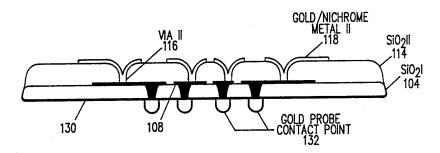


FIG. 9

DOCKET A L A R M

Explore Litigation Insights



Docket Alarm provides insights to develop a more informed litigation strategy and the peace of mind of knowing you're on top of things.

Real-Time Litigation Alerts



Keep your litigation team up-to-date with **real-time** alerts and advanced team management tools built for the enterprise, all while greatly reducing PACER spend.

Our comprehensive service means we can handle Federal, State, and Administrative courts across the country.

Advanced Docket Research



With over 230 million records, Docket Alarm's cloud-native docket research platform finds what other services can't. Coverage includes Federal, State, plus PTAB, TTAB, ITC and NLRB decisions, all in one place.

Identify arguments that have been successful in the past with full text, pinpoint searching. Link to case law cited within any court document via Fastcase.

Analytics At Your Fingertips



Learn what happened the last time a particular judge, opposing counsel or company faced cases similar to yours.

Advanced out-of-the-box PTAB and TTAB analytics are always at your fingertips.

API

Docket Alarm offers a powerful API (application programming interface) to developers that want to integrate case filings into their apps.

LAW FIRMS

Build custom dashboards for your attorneys and clients with live data direct from the court.

Automate many repetitive legal tasks like conflict checks, document management, and marketing.

FINANCIAL INSTITUTIONS

Litigation and bankruptcy checks for companies and debtors.

E-DISCOVERY AND LEGAL VENDORS

Sync your system to PACER to automate legal marketing.

